

**Search Notes**

Application/Control No.

10/774,788

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

SHIN ET AL.

Art Unit

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	227.14, 227.16, 227.18, 227.23	9/19/2005	PL
385	12-13	9/19/2005	PL
385	31-32	9/19/2005	PL
385	37	9/19/2005	PL
356	32, 35.5	9/19/2005	PL
356	73.1	9/19/2005	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted w/ S. Allen	5/17/2005	PL
East (See attached)	5/18/2005	PL
East (See attached)	5/19/2005	PL
East (See attached)	9/19/2005	PL